Symbol	Parameter	Device*	Value	Units
TOTAL DE	VICE			
T _{STG}	Storage Temperature	All	-55 to +150	°C
T _{OPR}	Operating Temperature	All	-55 to +100	°C
T _{SOL}	Lead Solder Temperature	All	260 for 10 sec	°C
PD	Total Device Power Dissipation (-55°C to 50°C)	All	200	mW
EMITTER				
١ _F	Continuous Forward Current	814 Series 617, 817 Series	±50 50	mA
V _R	Reverse Voltage	617 Series 817 Series	6 6	V
P _D	LED Power Dissipation (25°C ambient) No derating up to 100°C	All	70	mW
DETECTO	3			
V _{CEO}	Collector-Emitter Voltage	All	70	V
V_{ECO}	Emitter-Collector Voltage	814, 817 Series 617 Series	6 7	V
Ι _C	Continuous Collector Current	All	50	mA
PD	Detector Power Dissipation (25°C ambient)	All	150	mW
	Derate above 90°C		2.9	mW/°C

Absolute Maximum Ratings (T_A = 25°C Unless otherwise specified.)

Electrical Characteristics (T_A = 25°C Unless otherwise specified.) **Individual Component Characteristics**

Symbol	Parameter	Test Conditions	Device	Min.	Typ.*	Max.	Unit
EMITTER							
V _F	Input Forward Voltage	I _F = 60mA	617 Series		1.35	1.65	V
		I _F = 20mA	817 Series		1.2	1.5	
		$I_F = \pm 20 \text{mA}$	814 Series		1.2	1.5	
I _R	Reverse Leakage	V _R = 6.0V	617 Series		.001	10	μA
	Current	V _R = 5.0V	817 Series	1			
DETECTO	R						
BV _{CEO}	Collector-Emitter Breakdown Voltage	$I_{\rm C} = 0.1 \text{ mA}, I_{\rm F} = 0$	ALL	70	100		V
BV _{ECO}	Emitter-Collector	I _E = 10 μA, I _F = 0	814, 817 Series	6	10		V
	Breakdown Voltage		617 Series	7	10		
I _{CEO}	Collector-Emitter Dark Current	V _{CE} = 10V, I _F = 0	H11AA814/A, 817 Series, H11A617C/D		1	100	nA
			H11A617A/B	1		50	

*Typical values at $T_A=25^{\circ}C$

H11AA814 Series, H11A617 Series, H11A817 Series Rev. 1.0.8

Symbol	DC Characteristic	Test Conditions	Device	Min	Тур*	Max	Unit
CTR	Current Transfer	$I_{F} = \pm 1 \text{mA}, V_{CE} = 5V^{(1)}$	H11AA814	20		300	%
	Ratio	$I_{F} = \pm 1 \text{mA}, V_{CE} = 5V^{(1)}$	H11AA814A	50		150	%
		$(I_F = 10 \text{mA}, V_{CE} = 5 \text{V}^{(1)}$	H11A617A	40		80	%
			H11A617B	63		125	%
			H11A617C	100		200	%
			H11A617D	160		320	%
		$(I_F = 5mA, V_{CE} = 5V^{(1)}$	H11A817	50		600	%
			H11A817A	80		160	%
			H11A817B	130		260	%
			H11A817C	200		400	%
			H11A817D	300		600	%
		$I_F = 1 \text{mA}, V_{CE} = 5 V^{(1)}$	H11A617A	13			%
			H11A617B	22			%
			H11A617C	34			%
			H11A617D	56			%
V _{CE (SAT)}	Collector-Emitter	$I_{\rm C} = 1$ mA, $I_{\rm F} = \pm 20$ mA	814 series			0.2	V
	Saturation Voltage	$I_{C} = 2.5 \text{mA}, I_{F} = 10 \text{mA}$ $I_{C} = 1 \text{mA}, I_{F} = 20 \text{mA}$	617 series			0.4	1
		$I_{\rm C} = 100$, $I_{\rm F} = 2000$	817 series			0.2	1
AC CHAF	ACTERISTIC						
t _r	Rise Time	$I_{C} = 2mA, V_{CE} = 2 V, R_{L} = 100\Omega^{(2)}$	ALL		4	18	μs
t _f	Fall Time	$I_{\rm C} = 2$ mA, $V_{\rm CE} = 2$ V, $R_{\rm L} = 100 \Omega^{(2)}$	ALL		3	18	μs

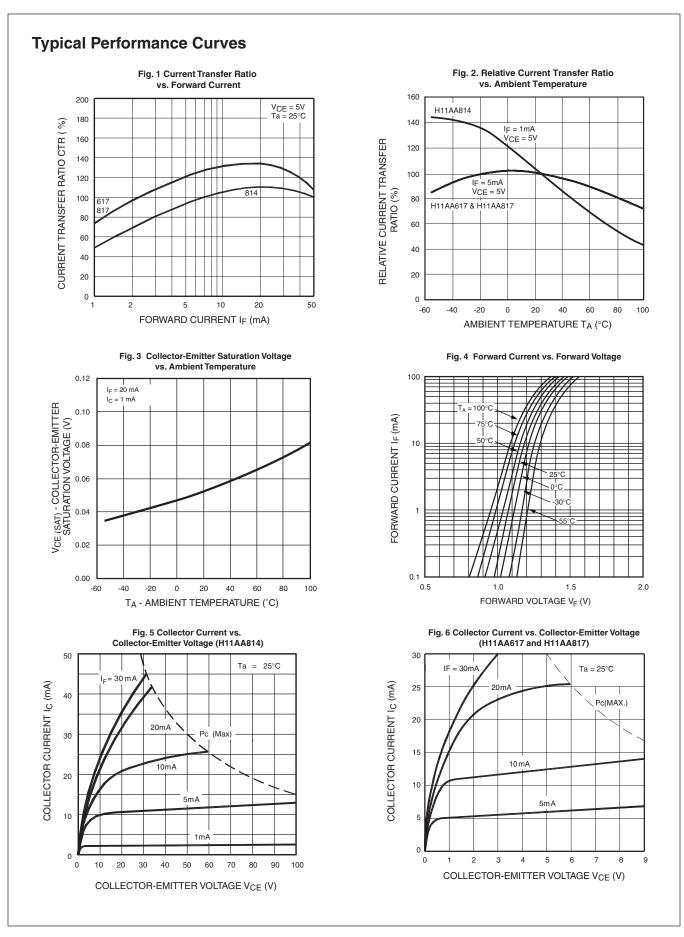
Isolation Characteristics

Symbol	Characteristic	Test Conditions	Min.	Тур.*	Max.	Units
V _{ISO}	Input-Output Isolation Voltage (note 3)	$\begin{array}{l} (f=60Hz,t=1\text{ min})\\ (I_{I\text{-}O}\leq 2\mu\text{A}) \end{array}$	5000			Vac(rms)
R _{ISO}	Isolation Resistance	(V _{I-O} = 500 VDC)	5x10 ¹⁰	10 ¹¹		Ω
C _{ISO}	Isolation Capacitance	(V _{I-O} = 0, f = 1 MHz)		0.6	1.0	pf

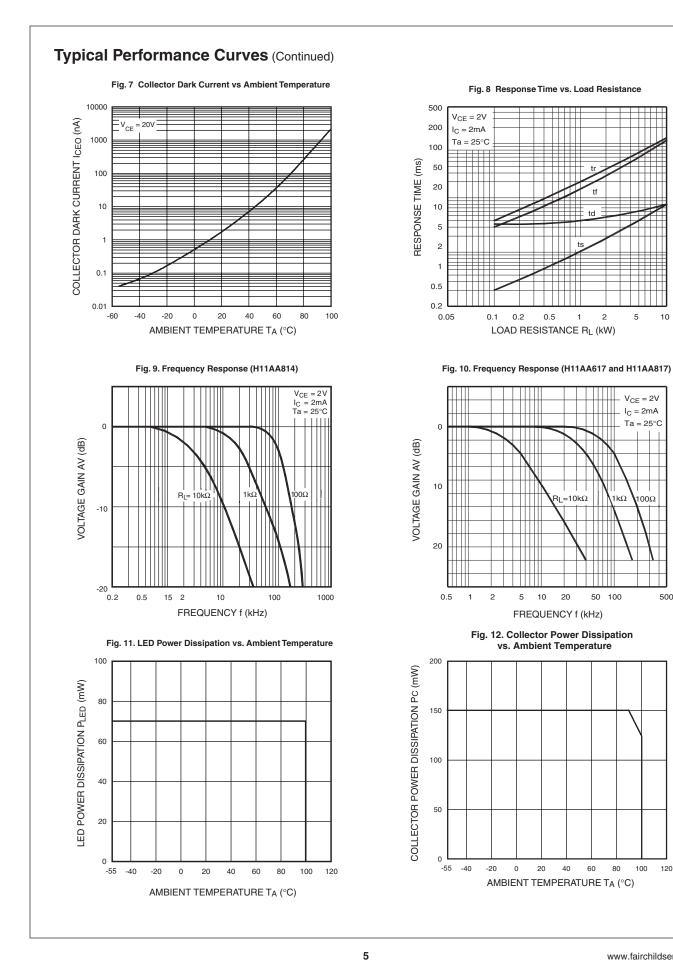
*Typical values at $T_A = 25^{\circ}C$.

Notes:

- 1. Current Transfer Ratio (CTR) = $I_C/I_F \times 100\%$.
- 2. For test circuit setup and waveforms, refer to Figure 13.
- 3. For this test, Pins 1 and 2 are common, and Pins 3 and 4 are common.



4



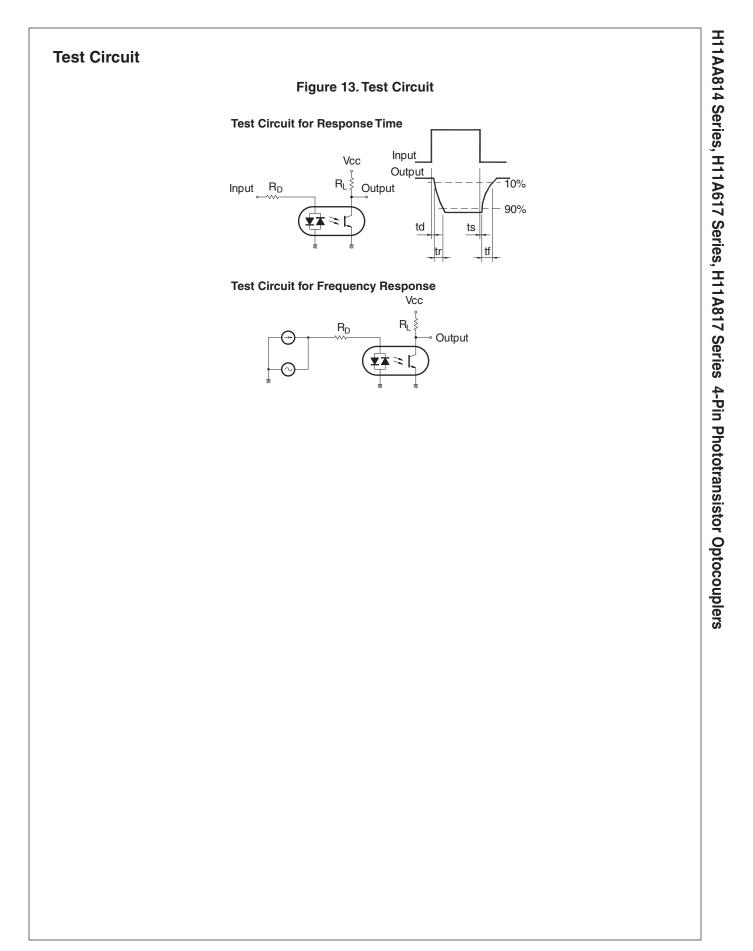


10

500

120

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Package Dimensions

0.200 (5.10) 0.161 (4.10)

0.157 (4.00)

0.020 (0.51) TYP

0.024 (0.60)

Through Hole

SEATING PLANE

0.150 (3.80)

0.4" Lead Spacing

0.130 (3.30) 0.091 (2.30)

ł

0.110 (2.79) 0.090 (2.29)

0.312 (7.92) 0.200 (5.10) 0.161 (4.10) 0.157 (4.00) 0.118 (3.00) 0.276 (7.00) 0.236 (6.00) SEATING PLANE 0.291 (7.40) 0.130 (3.30 0.110 (2.80) - 0.010 (0.26) 0.150 (3.80) 0.110 (2.79) 0.090 (2.29) 0.024 (0.60) 0.016 (0.40) 0.42 (10.66)

0.312 (7.92) 0.288 (7.32) 0.276 (7.00) 0.236 (6.00)

> 0.300 (7.62) typ

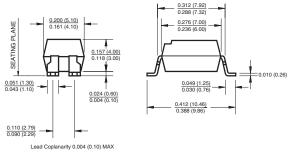
0.010 (0.26)

Note:

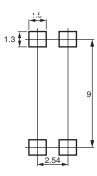
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All dimensions are in inches (millimeters)

Surface Mount



Footprint Dimensions (Surface Mount)



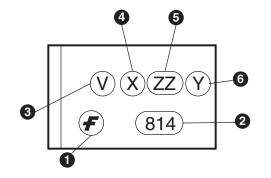
H11AA814 Series, H11A617 Series, H11A817 Series 4-Pin Phototransistor Optocouplers

Ordering Information

Part Number Example	Description
H11AA814S	Surface Mount Lead Bend
H11AA814SD	Surface Mount; Tape and reel
H11AA814W	0.4" Lead Spacing
H11AA814300	VDE Approved
H11AA814300W	VDE Approved, 0.4" Lead Spacing
H11AA8143S	VDE Approved, Surface Mount
H11AA8143SD	VDE Approved, Surface Mount, Tape & Reel

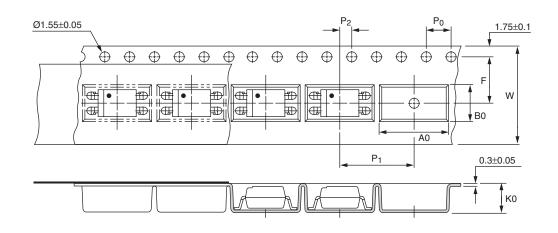
*To specify the new construction version which needs 260°C max reflow peak temperature rating: add "NF098" to the end of the part number. The non-NF098 version is rated for 260°C peak reflow temperature only for parts marked with date code 0550 and later.

Marking Information



Definiti	ions
1	Fairchild logo
2	Device number
3	VDE mark (Note: Only appears on parts ordered with VDE option – See order entry table)
4	One digit year code
5	Two digit work week ranging from '01' to '53'
6	Assembly package code

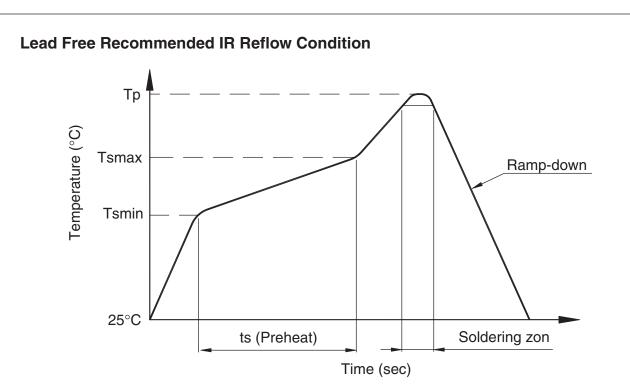
Carrier Tape Specifications



Note:

All dimensions are in millimeters

Description	Symbol	Dimensions in mm (inches)
Tape wide	W	16 ± 0.3 (.63)
Pitch of sprocket holes	P ₀	4 ± 0.1 (.15)
Distance of compartment	F P ₂	7.5 ± 0.1 (.295) 2 ± 0.1 (.079)
Distance of compartment to compartment	P ₁	12 ± 0.1 (.472)
Compartment	A0	10.45 ± 0.1 (.411)
	B0	5.30 ± 0.1 (.209)
	K0	4.25 ± 0.1 (.167)



Profile Feature	Pb-Sn solder assembly	Lead Free assembly
Preheat condition (Tsmin-Tsmax / ts)	100°C ~ 150°C 60 ~ 120 sec	150°C ~ 200°C 60 ~120 sec
Melt soldering zone	183°C 60 ~ 120 sec	217°C 30 ~ 90 sec
Peak temperature (Tp)	240 +0/-5°C	260 +0/-5°C
Ramp-down rate	6°C/sec max.	6°C/sec max.

Recommended Wave Soldering condition

Profile Feature	For all solder assembly
Peak temperature (Tp)	Max 260°C for 10 sec

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